						Sh	eet of 1
Substitute For	m PTO-1449		partment of Commerce t and Trademark Office	Attorney's Docket No 10555-022001).	Application No 09/840,003	3
JUN 0 2 2003	> t	y Applicant	atement	Applicant Marco Falcioni	, et al.	TECH	JUN OA SEL
	(Use several sheets if necessary) (37 CFR §1.98(b))				Filing Date April 19, 2001		ENTER 100
TRADEN							1000/2020
			U.S. Patent	Documents			1500
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						

	Foreig	n Patent Doo	uments or Pu	blished Foreign	Patent A	Application	าร	-
Examiner	Desig.	Document	Publication	Country or			Trans	lation
Initial	ID	Number	_ Date	Patent Office	Class	Subclass	Yes	No
	AC					1		
	AD					-		

Other Documents (include Author, Title, Date, and Place of Publication)						
Examiner Initial	Desig. ID	Document				
MPA	AE	HD. Klein, "Statistische Versuchsplanung", 1995, Nachr. Chem. Tech. Lab. Vol. 43, pp. 1078, 1080-1082 (with English translation).				
	AF					
	AG					
	AH					

Examiner Signature

 $\mathbf{A}\mathbf{B}$

Marianne P. allen

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

CL	1	. С	1
Sheet	- 1	of	- 1

(01	Substitute Form PTO-1449 (Modified)
70	Information
oct 1	7 7003 67) b
188	(27.65 \$1.09/5)

U.S. Department of Commerce Patent and Trademark Office

Attorney's Docket No. 10555-022001

Application No. 09/840,003

Information Disclosur Statement by Applicant (Use several sheets if necessary) Applicant

Marco Falcioni, et al.

Filing Date

Group Art Unit

§1.98(b)

April 19, 2001

1631

	U.S. Patent Documents						
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	,					
	AB						
	AC					The second discountry and the second discoun	
,	AD						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Trans Yes	lation No
mps	AE	WO02/04112	17/01/02	PCT				
	AF							
	AG							
	AH							·

	Other Documents (include Author, Title, Date, and Place of Publication)						
Examiner Initial	Desig. ID	Document					
	AI						
	AJ						
	AK						
	AL						

Examiner S	Signature
------------	-----------

Marano P. allen

Date Considered

1/26/04